



Photochemical removal of NO₂ by using 172-nm Xe₂ excimer lamp in N₂ or air at atmospheric pressure

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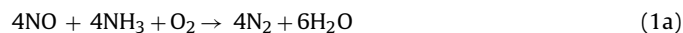
ABSTRACT

Photochemical removal of NO₂ in N₂ or air (5–20% O₂) mixtures was studied by using 172-nm Xe₂ excimer lamps to develop a new simple photochemical aftertreatment technique of NO₂ in air at atmospheric pressure without using any catalysts. When a high power lamp (300 mW/cm²) was used, the conversion of NO₂ (200–1000 ppm) to N₂ and O₂ in N₂ was >93% after 1 min irradiation, whereas that to N₂O₅, HNO₃, N₂, and O₂ in air (10% O₂) was 100% after 5 s irradiation in a batch system. In a flow system, about 92% of NO₂ (200 ppm) in N₂ was converted to N₂ and O₂, whereas NO₂ (200–400 ppm) in air (20% O₂) could be completely converted to N₂O₅, HNO₃, N₂, and O₂ at a flow rate of 1 l/min. It was found that NO could also be decomposed to N₂ and O₂ under 172-nm irradiation, though the removal rate is slower than that of NO₂ by a factor of 3.8. A simple model analysis assuming a consecutive reaction NO₂ → NO → N + O indicated that 86% of NO₂ is decomposed directly into N + O₂ and the rest is dissociated into NO + O under 172-nm irradiation. These results led us to conclude that the present technique is a new promising catalyst-free photochemical aftertreatment method of NO₂ in N₂ and air in a flow system.

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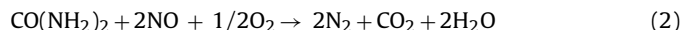
1. Introduction

Nitrogen oxides (NO_x: NO and NO₂), which arise from various industrial sources, are major contributors to the acid rain [1,2]. Removal methods of NO_x by using catalysts have been extensively studied and widely applied as aftertreatment techniques in automobiles and thermal power plants [3–5]. Catalysts must be not only active at low reaction temperatures in the presence of components such as O₂, CO, CO₂, H₂O, and hydrocarbons usually present in the exhausted gases, but also resistant to deactivation by SO₂. Selective catalytic reduction (SCR) is widely applied as a cleaning method of fuel gas. Removal processes of NO_x are as follows:



Non-selective catalytic reduction (NSCR) needs injection of NH₃ or other reducing agents without catalysts. The deNO_x reaction is as

follows:



In the above SCR and NSCR processes, such expensive reducing agents as NH₃ and CO(NH₂)₂ are required and global warming CO₂ gas is emitted in the NSCR process (2).

Removal of NO_x was also studied by using pulsed corona discharge [6–13] and microwave discharge methods [14–23]. Discharge methods will become a low cost convenient method, if NO_x can be removed without using any catalysts and reducing agents. In our previous study using microwave discharge, NO could be efficiently decomposed into N₂ and O₂ in N₂ at atmospheric pressure [19]. In most of the exhausted gases containing NO_x, O₂ less than 20% is usually involved. In such cases, it is generally very difficult to completely suppress NO_x emission resulting from plasma discharge of buffer N₂/O₂ gases without using catalysts. Recently, costs of rare metal catalysts increase greatly because of economic growth of developing countries. Therefore, a new low-cost and catalysts-free aftertreatment process in air must be developed to overcome this problem.

The reason why discharge processes are difficult to remove NO_x is that dominant energy carrier in electric discharges is energetic

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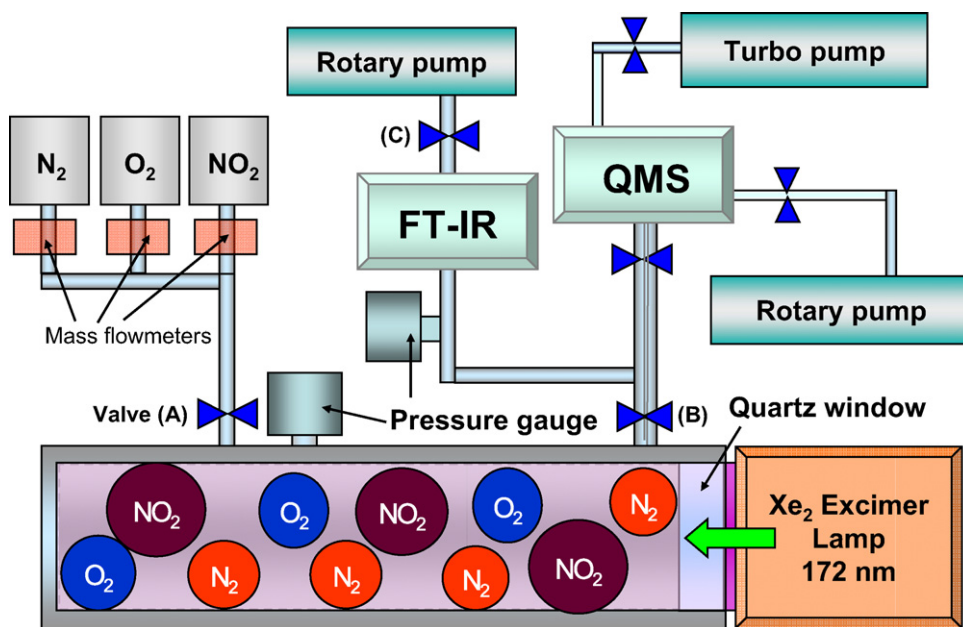


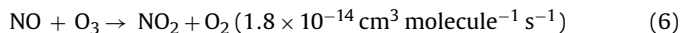
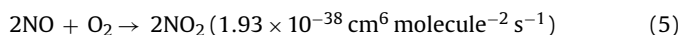
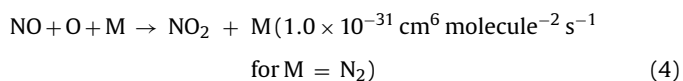
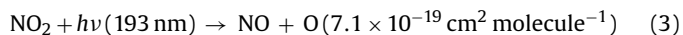
Fig. 1. deNO_x apparatus using a Xe₂ excimer lamp.

electrons. The disadvantage of discharge processes arises from a low selectivity of gas phase reactions of energetic electrons with NO_x and buffer N₂/O₂ gases. In an electric discharge of NO_x in air, electron-impact excitation, ionization, and dissociation of NO_x, N₂, and O₂ occur simultaneously and subsequent various secondary reactions lead to NO_x emission. Thus, a higher selectivity in gas phase reactions is required in order to remove NO_x efficiently in air.

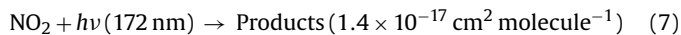
We have recently initiated a systematic study on photochemical removal of NO_x at atmospheric pressure in air [24–28]. An advantage of photochemical method is that more selective decomposition is possible than that in electric-discharge methods, because there are large differences in the absorption coefficients of gas components in exhausted gases. N₂ has no absorption in the 170–200 nm region, although it is easily decomposed and ionized in electric discharges by impact of accelerated electrons. If N₂, which is a major component in most of exhausted gases, is inert, reactions in the systems become simple and decomposition efficiencies of NO_x are expected to increase greatly.

By using this high selectivity in photoabsorption in the vacuum ultraviolet (VUV) region, we have recently attempted photochemical removal of NO₂ at atmospheric pressure by using a 193-nm ArF excimer laser [25] and a low-power (50 mW/cm²) 172-nm Xe₂ excimer lamp [28]. The former photon source was a high power pulse laser with a pulse width of about 25 ns, whereas the latter one was a continuous wave (CW) lamp. The advantages of the latter excimer lamp in comparison with that of the former excimer laser are compact size, low price, low running cost, and poisonous F₂ gas free.

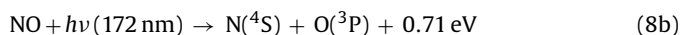
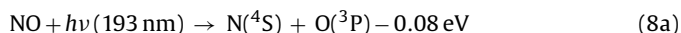
When 193-nm ArF excimer laser was used, more than 80% of NO₂ (200 ppm) could be converted into N₂, O₂, and NO in N₂ at atmospheric pressure. However, it was difficult to decompose NO₂ in air because after photolysis of NO₂ into NO + O (3), such backward reactions (4)–(6) occur significantly [1,25,28–31]:



The absorption cross section of NO₂ at 172 nm is about 20 times larger than that at 193 nm [31]:



The dissociation energy of NO (6.50 eV) is higher than the photon energy of 193-nm light (6.42 eV), whereas it is lower than that of 172-nm light (7.21 eV) [31,32]:



Therefore, NO can be energetically decomposed into N + O under 172-nm irradiation. We have recently studied photolysis of NO₂ by using a low power 172-nm Xe₂ excimer lamp (50 mW/cm²) [28]. It was found that the NO₂ conversion in N₂ was 99% and the formation ratios of N₂, O₂, NO, and N₂O were 47, 98, 0, and 2%, respectively, after 30 min irradiation. The NO₂ in air (5–20% O₂) could be efficiently converted to N₂O₅ and HNO₃ due to reactions by O₃ and H₂O (impurity) after only 1.0–1.5 min irradiation. All of the above experiments were carried out in a closed batch system. However, a continuous flow system is required for the practical use of the photochemical NO_x removal system. When we attempted to decompose NO_x in a flow system by using the ArF excimer laser and the low-power Xe₂ excimer lamp, it was difficult to remove NO_x probably due to slow removal rates. In the present study, we have used not only the low-power lamp (50 mW/cm²) but also a high-power (300 mW/cm²) Xe₂ lamp. Then, it was found that NO₂ (200–400 ppm) can be removed completely in air in a flow system. Possible photochemical processes are discussed using known photochemical and gas phase reactions [29–31].

2. Apparatus

Fig. 1 shows a deNO_x chamber having an inside volume of 185 cm³ used in this study. Light from an unfocused 172-nm Xe₂ lamp (USHIO, UER20H172: 50 or 300 mW/cm², 155–200 nm range) was used to remove NO_x at a room temperature. The low-power

Xe₂ lamp was a commercial product, whereas the high-power one was a trial product of USHIO Inc. The size of a low-power Xe₂ lamp (50 mW/cm²) was $\phi = 30$ mm and length = 200 mm, whereas that of a high-power Xe₂ lamp (300 mW/cm²) was $\phi = 70$ mm and length = 240 mm.

Experiments were carried out not only in a closed batch system used in the previous study [28] but also in a flow system. The total pressure was kept at atmospheric pressure and the NO₂ or NO concentration diluted in pure N₂ or air (5–20% O₂) was 200–1000 ppm (v/v). In the batch system, desired gas mixtures were introduced through mass flow controllers and valves (A) and (B) in Fig. 1 were closed. Then, the lamp was irradiated from the right side. In the flow system, stop valves (A)–(C) were open during experiments and the flow rates of each gas were controlled by mass flow controllers. It was kept at 1 l/min in the present experiments. The total pressure was controlled by using valve (B).

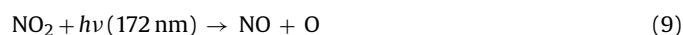
In the batch experiments, before and after photo-irradiation, outlet gases were analyzed by using HORIBA gas analysis system (FG122-LS) equipped with an FTIR spectrometer and ANELVA gas analysis system (M-200GA-DTS) equipped with a quadrupole mass spectrometer. On the other hand, outlet gases were analyzed on line by using the FTIR spectrometer in the flow experiments. The low sensitive mass spectrometer was used for the determination of N₂/O₂ ratios of buffer gases, whereas the high sensitive FTIR system was used for the detection of NO_x and O₃. The light path length and volume of analyzing chamber in FTIR was 2.4 m and 300 cm³, respectively. The spectra were measured in the 900–5000 cm⁻¹ region with an optical resolution of 4 cm⁻¹. The reliable calibration curves of NO_x (NO, NO₂, and N₂O) in FTIR measurements were supplied by HORIBA Inc. The detection limits of NO₂, NO, and N₂O were, 1, 1, and ~0.5 ppm, respectively, in our FTIR spectrometers. The concentrations of N₂O₅, HNO₃, and O₃ were evaluated by reference to their standard spectral data supplied by HORIBA Inc. The experimental accuracies in the measurements of concentrations of NO_x and O₃ were $\pm 3\%$. We determined the residual amount of NO_x, [NO_x]/[NO_x]₀, and the formation ratios of N₂, O₂, N₂O₅, and HNO₃ defined as [N₂]/[NO_x]₀, [O₂]/[NO_x]₀, [N₂O₅]/[NO_x]₀, and [HNO₃]/[NO_x]₀, respectively, from gas analyses. Here, [NO_x]₀ is an initial concentration of NO_x. N₂ and O₂ cannot be detected by FTIR, because these diatomic molecules are inactive for IR light. If other NO_x such as N₂O and N₂O₅ and O₃ are produced in the photolysis, all of them can be detected. Thus, the formation ratios of N₂ and O₂ in N₂ were determined from N and O balance before and after photolysis respectively.

The following gases were used without further purification: N₂ (Taiyo Nissan Inc.: purity >99.9998%), O₂ (Nippon Sanso Inc.: purity >99.99995%), NO₂ (Nippon Sanso Inc.: 3630 ppm in high purity N₂), NO (Taiyo Sanso Inc.: 2.02% in high purity N₂), and N₂O (Nippon Sanso Inc.: 959 ppm in high purity). NO₂ and NO were diluted in N₂ or N₂/O₂ mixtures before use.

3. Results and discussion

3.1. NO₂ removal in N₂ in a batch system

At first, the decomposition of NO₂ in N₂ was studied by using low-power (50 mW/cm²) and high-power (300 mW/cm²) lamps in a closed batch system. When the low-power lamp was used, besides NO₂ bands at about 1630 and 2920 cm⁻¹, a weak NO band appeared around 1840 cm⁻¹ after 172-nm irradiation. This indicates that the following reaction pathway is open:



On the other hand, no NO band was observed by using the high-power lamp. On the basis of this fact, it is reasonable to assume that NO formed through process (9) can efficiently be converted to N₂ and O₂ at the high power probably due to subsequent photolysis of NO (10) and secondary reactions (11)–(13) [29–31]:

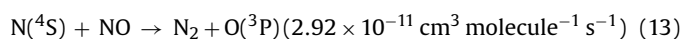
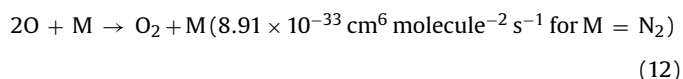
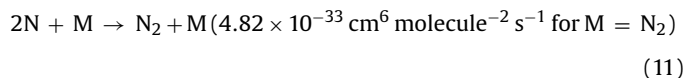


Fig. 2a and b shows the dependence of residual amount of NO₂ and the formation ratios of NO, N₂O, N₂, and O₂ on the irradiation time of lamp in N₂ obtained by using the two lamps at an initial NO₂ concentration of 1000 ppm. When the low-power lamp was used, the residual amount of NO₂ decreases to 25% after 5 min and slowly decreases to 7% after 30 min photo-irradiation, whereas the formation ratio of N₂ and O₂ increases to 46 and 93%, respectively. The formation ratio of NO initially increases to 6% until 5 min then gradually decreases to 0% in the 5–20 min range. The formation ratio of N₂O was less than 1% in the all time range. When the high-power lamp was used, decomposition rate of NO₂ increases significantly and the formation of NO and N₂O was not observed. The residual amount of NO₂ rapidly decreases to 7% after 1 min irradiation and slowly decreases to zero in the 1–30 min range. There are small parts like a vacuum gauge, which got little VUV light in the photolysis chamber. This may be one reason for the slow decrease in the residual amount of NO₂ in the 1–30 min range, though a further experiment is necessary to conclude the validity of this explanation. The formation ratios of N₂ and O₂ increase rapidly to 46 and 93% at 1 min and become 50 and 100% after 30 min irradiation. On the basis of these results, NO₂ can be efficiently decomposed to N₂ and O₂ in N₂ at 1 atm keeping NO and N₂O emissions at low levels under 172-nm irradiation.

3.2. NO removal in N₂ in a batch system

In order to confirm the contributions of processes (10)–(13), the photolysis of NO under 172-nm irradiation was also studied. Fig. 3a and b shows the dependence of residual amount of NO and the formation ratios of NO₂, N₂O, N₂, and O₂ on the irradiation time in N₂ obtained by using the two lamps at an initial NO concentration of 1000 ppm. When the low-power lamp was used, the residual amount of NO decreases to 59 and 37% after 5 and 10 min irradiation, whereas the formation ratio of NO₂ increases to 10% in the 0–10 min range and slowly decreases to 4% in the 10–30 min range. The formation of a small amount of N₂O less than 2% was observed in the all time range. When the high-power lamp was used, the decomposition rate of NO increases significantly. The residual amount of NO rapidly decreases to 6% after 5 min irradiation and slowly decreases to zero in the 5–20 min range. Although N₂O was not produced, NO₂ was observed in the short time range below about 5 min. Its formation ratio has a peak (~10%) at 1 min. The formation ratios of N₂ and O₂ increase rapidly to 46 and 47% at 5 min and become ~50% after 30 min irradiation. On the basis of these results, NO can be efficiently decomposed to N₂ and O₂ in N₂ keeping NO₂ and N₂O emissions at low levels under 172-nm irradiation.

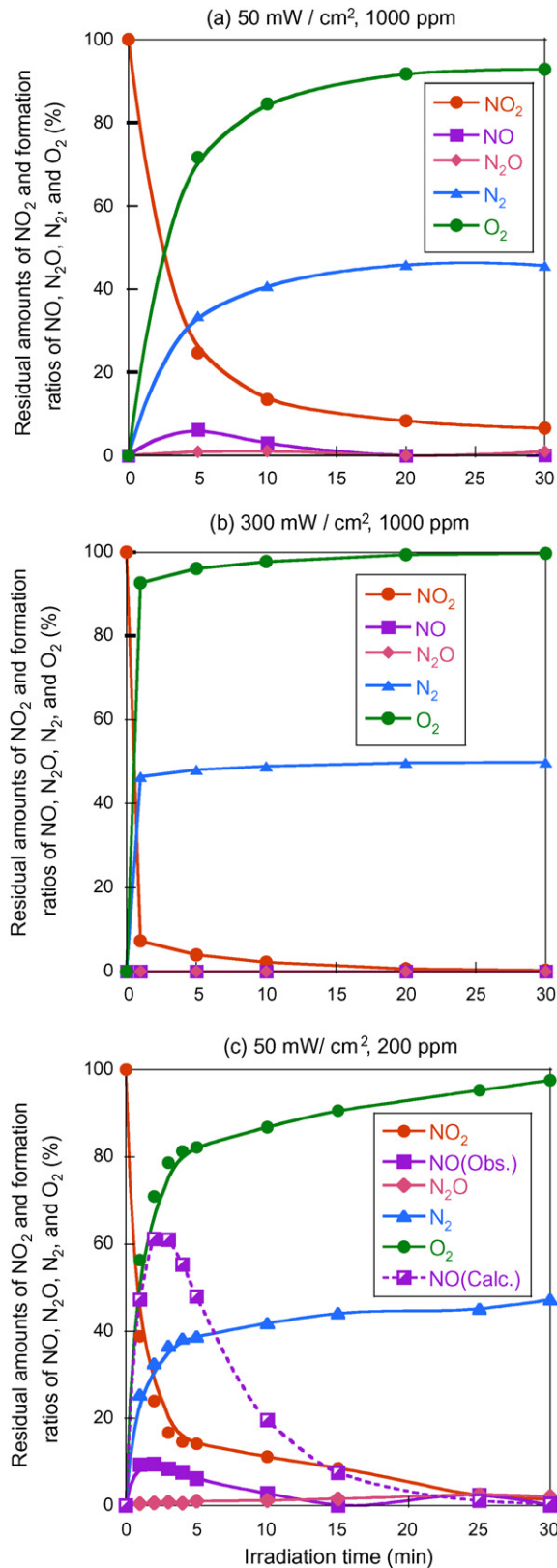


Fig. 2. Dependence of the residual amount of NO_2 and the formation ratios of NO_2 , NO , N_2O , N_2 , and O_2 on the irradiation time in N_2 .

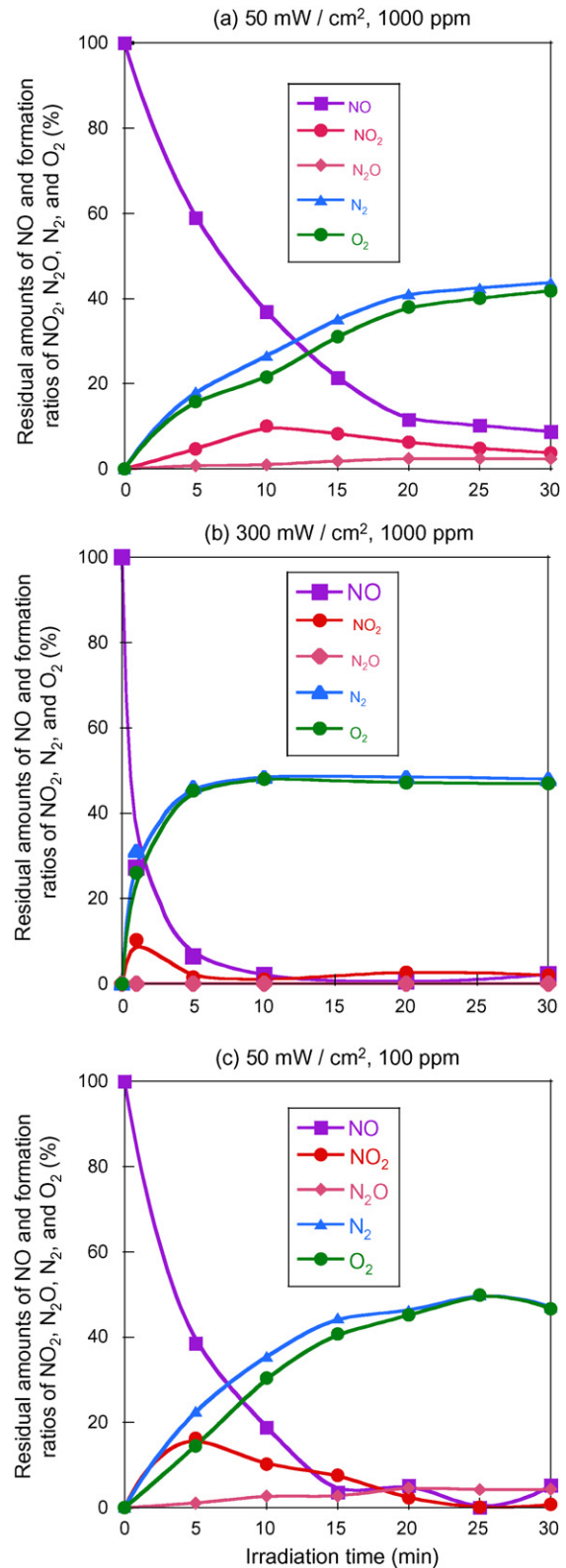


Fig. 3. Dependence of the residual amount of NO and the formation ratios of NO_2 , N_2O , N_2 , and O_2 on the irradiation time in N_2 .

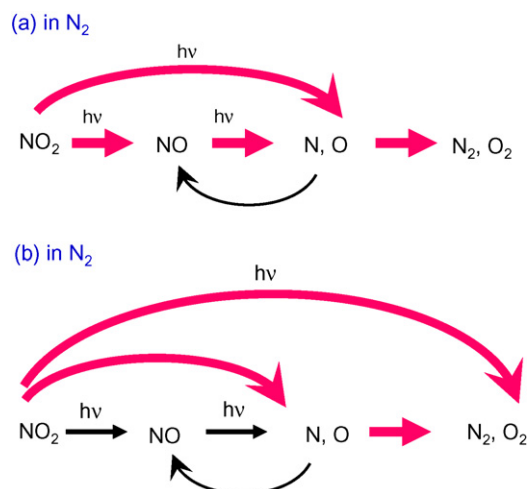


Fig. 4. Two typical models of major decomposition processes of NO_2 in N_2 under 172-nm irradiation.

3.3. Mechanism of NO_2 removal in N_2 in a batch system

The reaction mechanism of NO_2 in N_2 under 172-nm irradiation is discussed from known photochemical and chemical reactions [29–31]. We found here that NO_2 is efficiently decomposed into N_2 and O_2 under 172-nm light in N_2 atmosphere keeping the formation ratios of NO and N_2O at low levels (<10%). Although the total absorption coefficient of NO_2 at 172 nm is known [31], little information on their products and yields has been reported to the best of our knowledge. However, kinetic analysis of the time profile of NO concentration provides useful information on the photolysis of NO_2 under 172-nm irradiation.

Two reaction models were considered here for the photolysis of NO_2 under 172-nm irradiation. Fig. 4a shows the first model as major decomposition processes of NO_2 in N_2 , where major pathways are shown by bold red lines and minor pathways are given by thin black lines. NO_2 is initially dissociated into $NO + O$. Then, the product NO is dissociated into $N + O$. The three-body recombination reactions of $2N + M$ and $2O + M$ led to N_2 and O_2 , which are major final products. When NO is produced from the three-body reaction $N + O + M$, NO is produced again. The relative contribution of the $N + O + M$ reaction to those of $2N + M$ and $2O + M$ reactions becomes small with increasing the reaction time, because NO concentration decreases with increasing the reaction time. Then, it is finally converted to N_2 and O_2 at a long irradiation time.

The most important finding in the present study is that no NO is produced by using the high-power lamp. In our separate experiment using pure NO (see Section 3.2), we found that the conversion of NO into N_2 and O_2 really occurs under 172-nm photolysis. The removal rates of NO_2 and NO under 172-nm irradiation were determined assuming that they obey the following simple first order decay of molecules:

$$[NO_2] = [NO_2]_0 \exp(-k_1 t) \quad (14a)$$

$$[NO] = [NO]_0 \exp(-k_2 t) \quad (14b)$$

The k_1 value was estimated to be $1.10 \times 10^{-2} s^{-1}$ by using removal data at a low NO_2 concentration of 200 ppm (Fig. 2c), where secondary reactions were expected to be reduced than those at 1000 ppm. In this concentration, a small amount of NO (<20 ppm) is produced. It was difficult to estimate a reliable removal rate of NO under such a low concentration in our FTIR spectrometer, the removal rate of NO was determined by using data at 100 ppm (Fig. 3c). It was $2.86 \times 10^{-3} s^{-1}$, which is smaller than that of NO_2

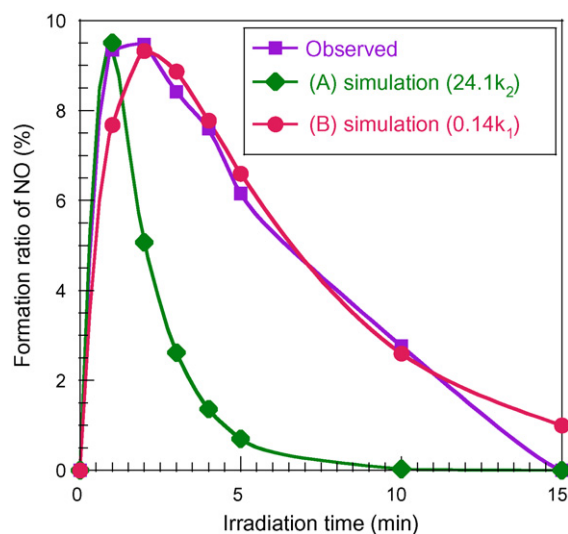


Fig. 5. Dependence of the residual amount of NO_2 and the formation ratio of NO on the irradiation time in N_2 obtained by experiment and consecutive reaction models using various rate constants.

by a factor of 3.8. We estimated these k_1 and k_2 values from linear first order decay plots. The correlation kinetic coefficients (R^2) of k_1 and k_2 values in the linear plots were 0.928 and 0.941, respectively. It is therefore reasonable to assume that removal rates of NO_2 and NO under 172-nm obey the simple first order.

Assuming a simple consecutive reaction in the 172-nm photolysis of NO_2 :

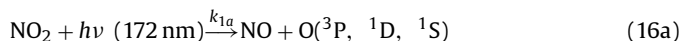


the concentrations of NO_2 and NO under the low-power lamp irradiation were calculated as a function of irradiation time using above k_1 and k_2 values. In the consecutive reaction (15), since the rate-determining step is the secondary photolysis of NO , NO will be observed as a major product. The calculated NO concentrations after photo-irradiation are shown in Fig. 2c (broken line) together with the experimental data for comparison. It should be noted that the maximum NO concentration at 2 min predicted from model calculations is higher than the observed one by a factor of 6.5. On the basis of these facts, the experimental data cannot be reproduced from the above simple consecutive reaction. There are two possible reasons for the explanation of this discrepancy between model (a) and experimental data.

One possible reason is the contribution of vibrationally excited states of NO produced through the $NO_2 + h\nu(172 \text{ nm}) \rightarrow NO^* + O$ photolysis. Unfortunately, no data on the initial vibrational distributions of $NO(X^2\Pi; v'')$ under 172-nm irradiation has been reported. However, it is known that vibrationally excited $NO(X^2\Pi; v'' \leq 14)$ levels are initially produced after 193-nm ArF laser photolysis of NO_2 [33,34]. Since the excitation energy of 172 nm (7.21 eV) is much higher than that of 193 nm (6.42 eV), product $NO(X; v'')$ molecules will be more vibrationally excited. If such vibrationally excited levels absorb 172-nm light again, NO will be excited into higher excited states, from which predissociation to $N + O$ atoms occurs more rapidly than that produced from the $NO(X; v'' = 0)$ level. When k_2 values were changed to reproduce experimental data, the best fit k_2 value for the peak value was $6.89 \times 10^{-2} s^{-1}$, as shown in Fig. 5 (case (A)). This value was 24.1 times larger than the observed k_2 value. No reasonable agreement between observed and calculated values was obtained because the calculated value decreases more rapidly than the observed one after about 1 min.

It is known that vibrationally relaxation is fast for excited states of $\text{NO}(X:v'' > 0)$ by collisions with NO_2 [33–35]. Thus, at high NO_2 concentration, vibrational relaxation by collisions with NO_2 becomes significant. In such a case, excitation into high-energy pre-dissociation states will be suppressed and the product distribution reflects simple photolysis of $\text{NO}(X:v'' = 0)$ into $\text{N} + \text{O}$ expressed by the measured k_2 value. If vibrational relaxation by collisions with NO_2 becomes insignificant, NO concentration will decrease with decreasing NO_2 concentration. Fig. 2c shows the experimental data at a low NO_2 concentration of 200 ppm. The maximum formation ratio of NO at 200 ppm is about 9% at 1–2 min, which is higher than that at 1000 ppm (6%). On the basis of this fact, it was concluded that the contribution of vibrationally excited NO^* was insignificant under the present experimental conditions.

The other possible reason is a direct pathway leading to $\text{N} + \text{O}_2$ besides $\text{NO} + \text{O}$ pathway:



Here, the following relation $k_1 = k_{1a} + k_{1b}$ holds. In this case the concentration of NO is given by

$$[\text{NO}] = \frac{k_{1a}}{\{k_2 - (k_{1a} + k_{1b})\}} [\exp\{-(k_{1a} + k_{1b})t\} - \exp(-k_2t)] [\text{NO}_2]_0 \quad (17)$$

When various k_{1a} and k_{1b} values are used to reproduce the experimental data, the best-fit curve was obtained at $k_{1a} = 1.8 \times 10^{-3} \text{ s}^{-1}$ and $k_{1b} = 1.08 \times 10^{-2} \text{ s}^{-1}$, as shown in Fig. 5 (case (B)). Therefore, the branching ratios of (16a) and (16b) were estimated to be 14 and 86%, respectively. This shows that the direct formation process of O_2 is faster than that of NO by a factor of 6. Thus, the revised second decomposition model (b) is shown in Fig. 4b, where the direct photolysis of NO_2 to $\text{N} + \text{O}_2$ is significant.

3.4. NO_2 removal in air in a batch system

Since small amounts of O_2 (5–20%) are involved in N_2/O_2 mixtures in the practical fuel combustion gases, removal techniques of NO_2 must be developed in air. The most outstanding difference between 172-nm irradiation and 193-nm one in air is that the absorption coefficient of O_2 at 172 nm ($4.6 \times 10^{-19} \text{ cm}^2 \text{ molecule}^{-1}$) is 1440 times larger than that at 193 nm ($3.2 \times 10^{-22} \text{ cm}^2 \text{ molecule}^{-1}$) [31]. Thus, higher concentrations of O_3 are produced in the reaction system in the presence of O_2 .

Fig. 6a and b shows FTIR spectra observed before and after 172-nm photolysis of NO_2 (200 ppm) in air (O_2 5%) using the low-power lamp. Before photolysis, strong NO_2 peak is observed. After 1 min photo-irradiation, the spectrum changed significantly, and NO_2 peak disappeared and N_2O_5 , HNO_3 , and O_3 peaks are observed. We have measured the dependence of residual amount of NO_2 and the formation ratios of products on the irradiation time of lamp at various O_2 concentrations in the 5–20% range. As a typical example, Fig. 7a and b shows results obtained in air (O_2 5%) by using the two lamps at an initial NO_2 concentration of 200 ppm. NO_2 can be efficiently converted to N_2O_5 and HNO_3 in the presence of O_2 due to the efficient formation of O_3 by photolysis of O_2 under 172-nm irradiation. At the NO_2 concentration of 200 ppm, NO_2 can be removed after about 1 min by using the low-power lamp and only 5 s by using the high-power lamp.

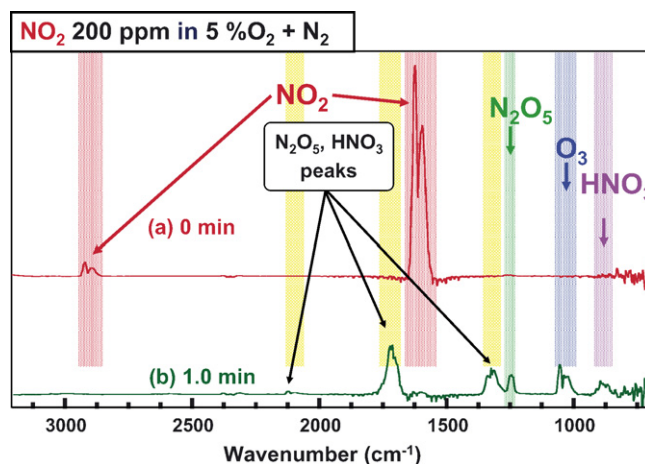


Fig. 6. FTIR spectra of NO_2 in air (5% O_2) under 172-nm irradiation observed at 0 and 1.0 min. The initial NO_2 concentration was 200 ppm.

3.5. NO_2 removal in N_2 and air in a flow system

For the actual application of photochemical removal of exhausted gases, a flow system, in which continuous removal of exhausted gases is possible, is required. We found that it was diffi-

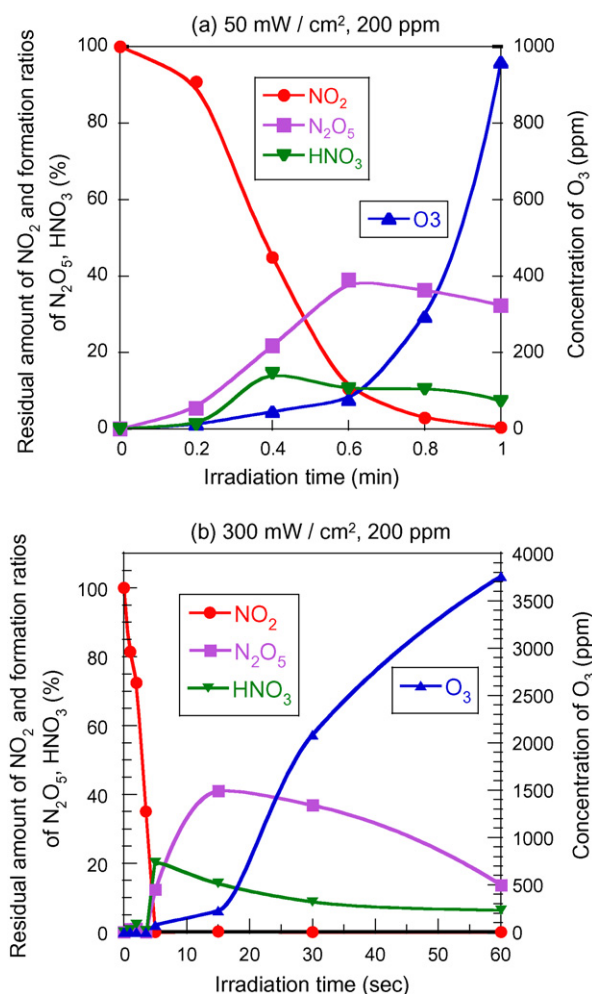


Fig. 7. Dependence of residual amount of NO_2 and the formation ratios of products on the irradiation time in air (5% O_2). The initial NO_2 concentration was 200 ppm.

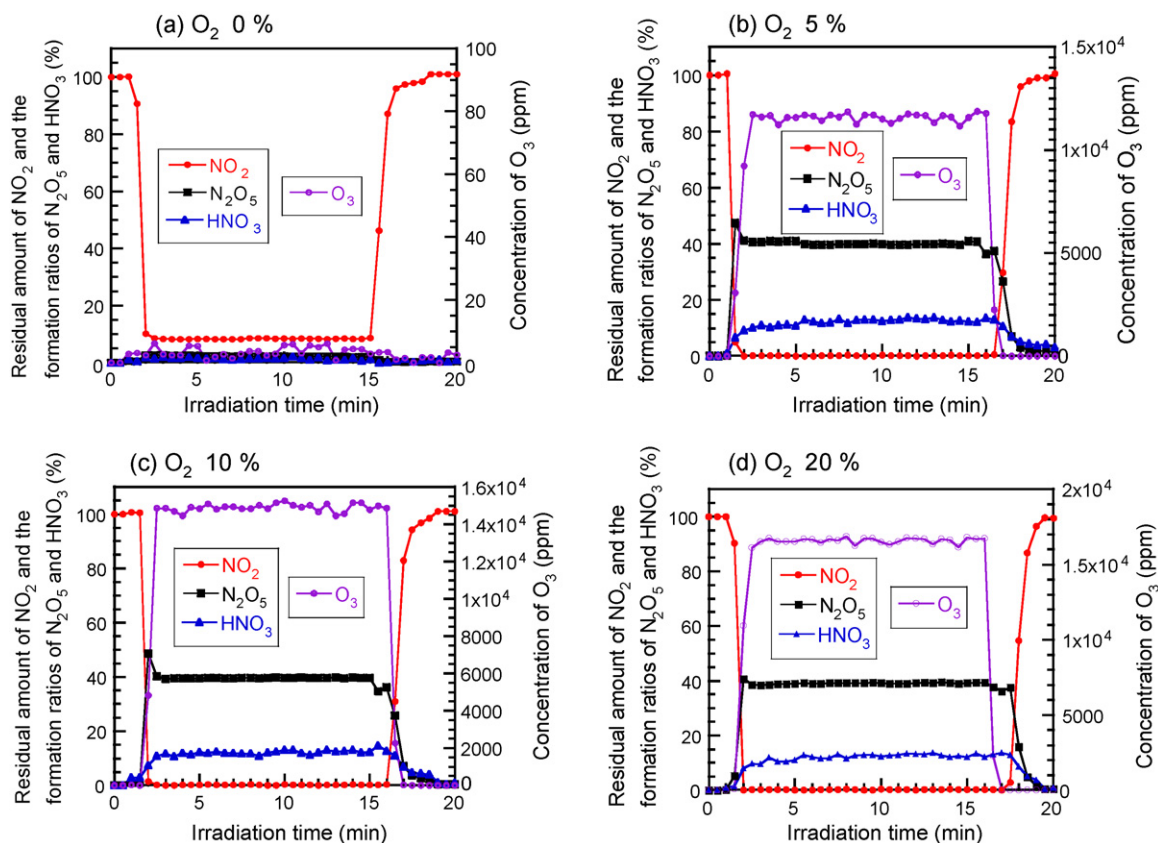


Fig. 8. Dependence of the residual amount of NO₂, the formation ratios of products, and the concentration of O₃ on the irradiation time in a flow system. Lamp was switched on at 1 min and off at 16 min. The initial NO₂ concentration was 200 ppm.

cult to efficiently decompose NO₂ in the flow system by using the low-power lamp. However, the flow system could be applied to the removal of NO₂, when the high-power lamp was used. Fig. 8a–d shows the dependence of residual amount of NO₂ and the formation ratios of NO₂, N₂O₅, and HNO₃ and concentration of O₃ on the irradiation time of lamp in the flow system in air (0, 5, 10, and 20% O₂), when 200 ppm of NO₂ was used. The Xe₂ lamp was switched on at 1 min and switched off at 16 min. In N₂ atmosphere, about 90% of NO₂ was dominantly converted to N₂ and O₂ at a steady state conditions. Small amounts of N₂O₅ and HNO₃ were also produced as minor products at low formation ratios of 2 and 1.5%, respectively. It should be noted that NO₂ can be completely converted after the lamp was switched on about 1 min in air (5–20% O₂). The formation ratios of N₂O₅ and HNO₃ were nearly constants at ~40 and ~12%, respectively, in this O₂ concentration range. On the basis of N balance, about ~92% of NO₂ is converted to N₂O₅ and HNO₃, and the rest of it is converted to N₂ and O₂ with the formation ratios of ~4 and ~8%, respectively. The concentration of O₃ increases to 12,000, 15,000, and 16,600 ppm with increasing the O₂ concentration from 5 to 20%. These results indicate that NO₂ can be removed efficiently in the flow system as N₂ and O₂ in N₂ and N₂O₅, HNO₃, N₂, and O₂ in air under 172-nm excimer lamp irradiation.

The maximum amount of NO₂, which can be removed in our flow system, was evaluated by changing the NO₂ concentration. Fig. 9 shows the dependence of the residual amount of NO₂ on the initial concentration of NO₂ in air (20% O₂). It was found that NO₂ can be removed in the 200–400 ppm range, whereas the residual amount of NO₂ slightly decreases from 70 to 60% with increasing the NO₂ concentration from ~500 to ~1000 ppm. In order to convert NO₂ to N₂O₅ and HNO₃, sufficient amounts of O₃ are necessary as discussed in Section 3.6. The main reason why the NO₂

cannot be removed more than 40% with increasing the NO₂ initial concentration from ~500 to ~1000 ppm is insufficient amounts of O₃ to convert all NO₂. The main products in the 200–400 ppm were N₂O₅ and HNO₃ and O₃, whereas they were N₂ and O₂ in the 500–1000 ppm range. Since the flow rate of our experiment was kept at 1 l/min, 16 μmol/min of NO₂ can be removed in our present system in air (20% O₂).

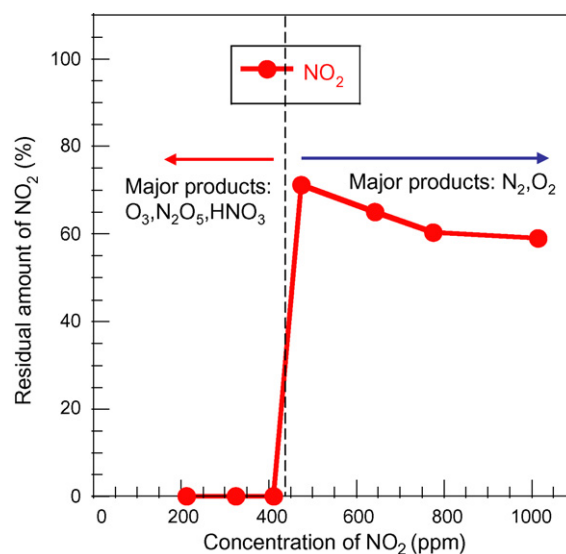


Fig. 9. Dependence of the residual amount of NO₂ on the initial concentration of NO₂ in a flow system in air (20% O₂).

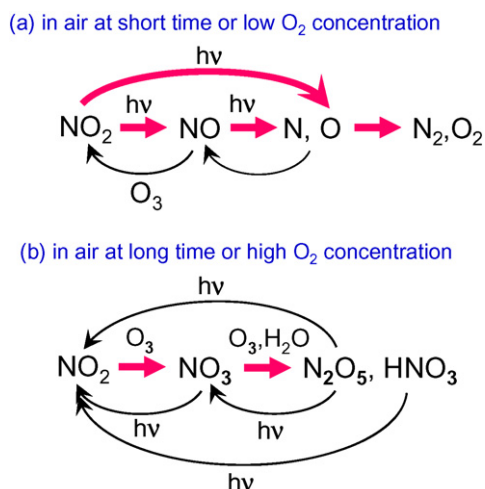
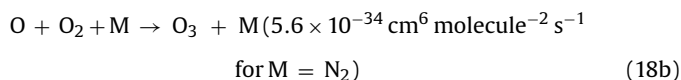
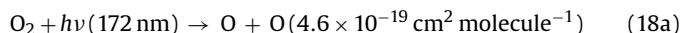


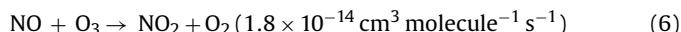
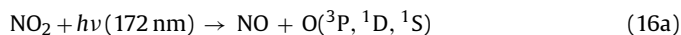
Fig. 10. Two models of major decomposition processes of NO₂ in O₂ under 172-nm irradiation.

3.6. The mechanism of NO₂ removal in air under 172-nm irradiation

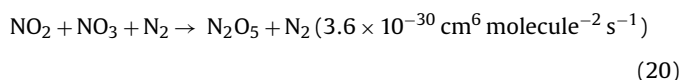
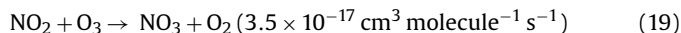
The reaction mechanism of NO₂ in air is discussed from known photochemical and gas phase reactions [29–31]. There are two cases for the NO₂ removal process in air. The first case occurs at a short time or low O₂ concentrations (model (a) in Fig. 10), whereas the second case happens at a long time or high O₂ concentrations (model (b) in Fig. 10). The initial step is slow photolysis of NO₂ to N₂ and O₂ without the presence of O₃. In this step, O₃ is produced via famous VUV photolysis of O₂ followed by the three-body reaction:



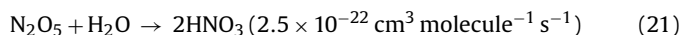
At short irradiation times, the concentrations of NO₂ and NO after photolysis of NO₂ are high, whereas the concentration of O₃ is low. Under these conditions, O₃ is completely consumed through the following processes:



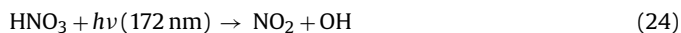
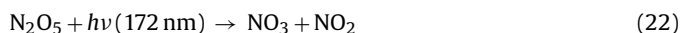
These cyclic reactions, which are famous reactions as destruction of ozone layer in the upper atmosphere [1], occur significantly. In this case, concentrations of NO and O₃ are either zero or very low. In the second step, the concentration of O₃ becomes sufficiently high, so that extra O₃ is accumulated in the photolysis chamber. In such a case, O₃ concentration is higher than that required for (6) and the reaction of excess O₃ with NO₂ leading to N₂O₅ takes place:



In the photolysis chamber, there is a small amount of residual H₂O (~90 ppm), as observed OH peaks from residual H₂O in FTIR spectra. N₂O₅ has a high reactivity with H₂O leading to HNO₃:



Thus, HNO₃ peaks arise from the result of reaction (21). Reaction (21) is an important reaction, because N₂O₅ can be easily removed as HNO₃ by the addition of H₂O. The following backward photolysis reactions must occur competitively under 172-nm irradiation:



However, the conversion of NO₂ to N₂O₅, HNO₃, N₂, and O₂ occurs completely. This indicates that these reactions are suppressed completely because dark reactions occur between the photolysis chamber and the gas analysis chamber at high O₃ concentrations.

The reaction mechanism of NO₂ in air (5–20% O₂) in the flow system is expected to be similar to that of the second step, because excess amounts of O₃ were always present in the photolysis chamber. In such a condition, oxidation reactions of NO₂ leading to N₂O₅ and subsequent reaction between N₂O₅ and H₂O leading to HNO₃ become significant. This process occupies about 92% of the total conversion of NO₂ and the rest is the conversion to N₂ and O₂ via photolysis.

4. Conclusion

In summary, deNO_x process by using 172-nm excimer lamp has been studied to develop a new photochemical removal process without using any catalysts. It was found that 200–400 ppm of NO₂ can be efficiently converted to N₂ and O₂ in N₂ and to N₂O₅ and HNO₃ in air in a flow system by using a high-power Xe₂ lamp (300 mW/cm²). N₂O₅ can be easily converted to HNO₃ by the addition of H₂O, and N₂O₅ and HNO₃ can be easily trapped in water and several reduction processes of NO₃⁻ anions to N₂ in water have already been developed at normal temperatures and pressures. Therefore, by combination the present method with such processes, a new photochemical aftertreatment technique of NO₂ in N₂ and air without using any catalysts will be developed. In air, O₃ was used as a key material in this aftertreatment technique of NO₂. Since O₃ is a source gas of photochemical smog, its emission should also be suppressed. In our present flow system, it is possible to suppress O₃ concentration by monitoring and controlling O₃ concentration in the exhausted gases. Thus, O₃ emission will not be a great problem in our apparatus. Unfortunately, little information on products and their yields has been reported for 172-nm photolysis of NO_x, O₂, and O₃. Therefore, such fundamental information is required for the improvement of the present photochemical process. In addition, for the practical application of photochemical process for NO₂ removal, effects of other emitting species such as SO₂, CO, CO₂, hydrocarbons, H₂O, and particulate matter, which are generally involved in the exhausted gases, must be examined.

Acknowledgements

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